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STATEMENT BY APPLICANT**

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Complete if Known

Application Number	10/828,508-Conf. #9644
Filing Date	April 20, 2004
First Named Inventor	Frank S. Bono
Art Unit	N/A
Examiner Name	Not Yet Assigned
Attorney Docket Number	101896-0232

Sheet	1	of	1
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Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number	Kind Code ² (if known)				
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		Country Code ³	Number-Kind Code ⁴ (if known)				
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

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Examiner Signature		Date Considered	11/14/05
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